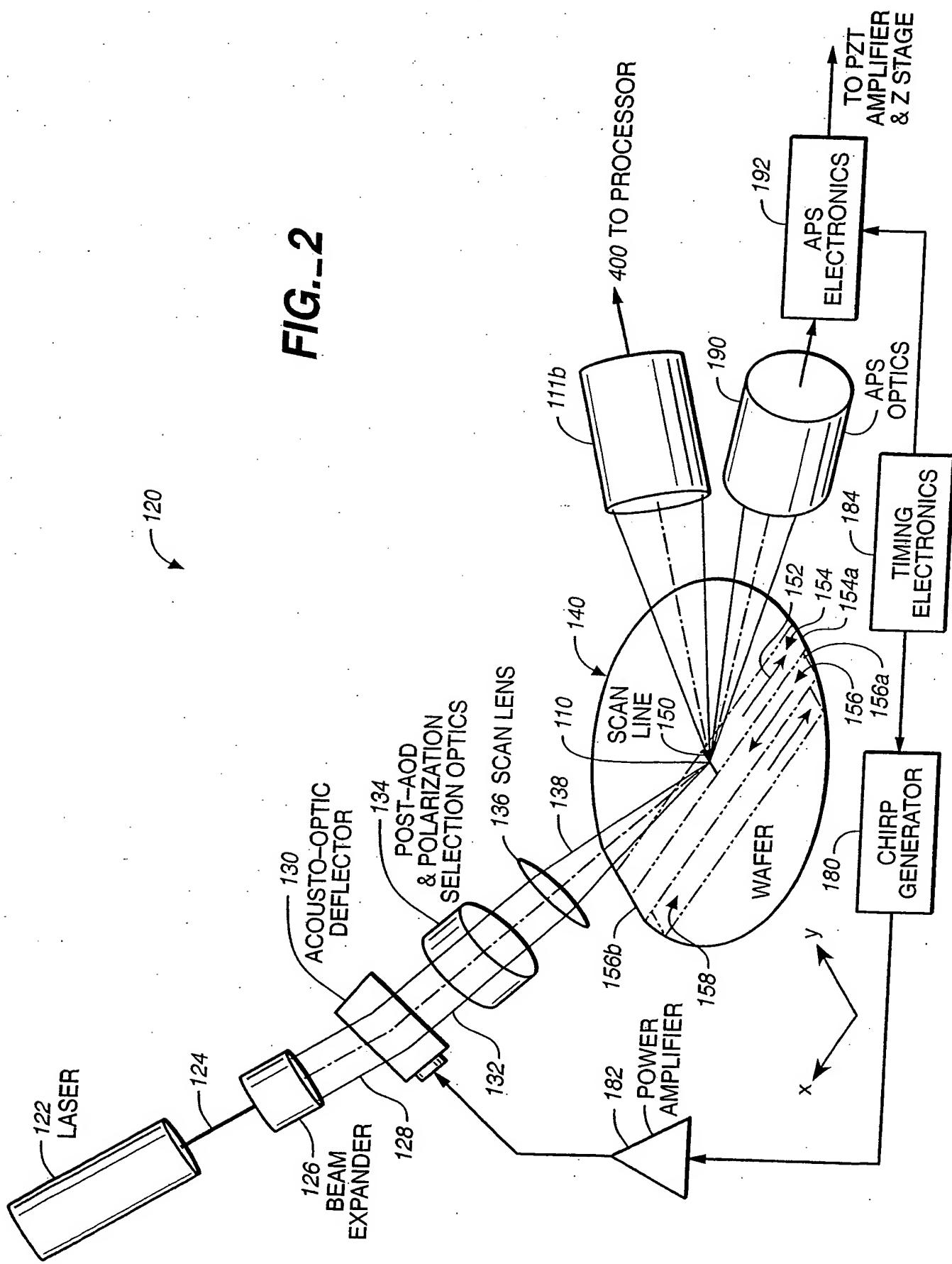
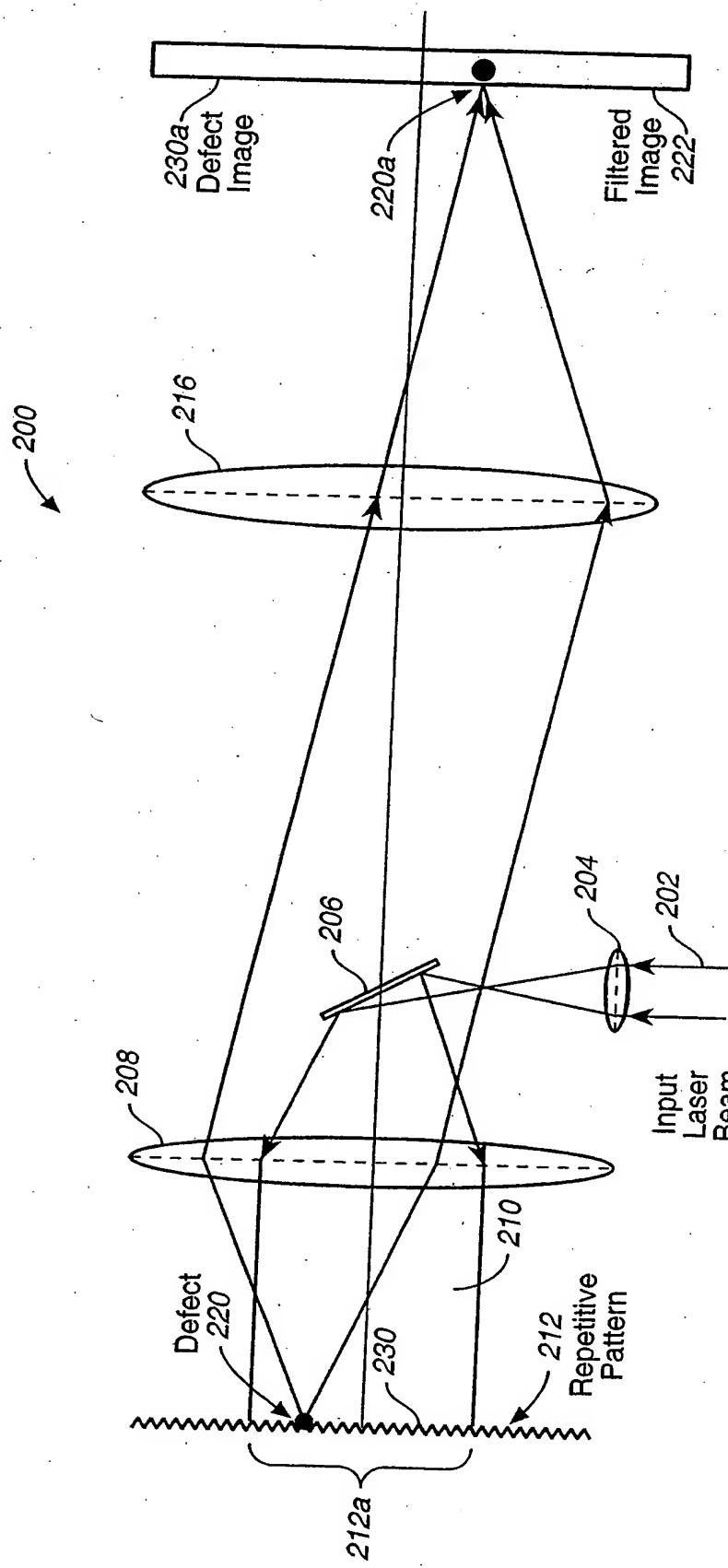


FIG. 1

FIG. 2





Optical Pattern Filtering Defect Detection

FIG.-3

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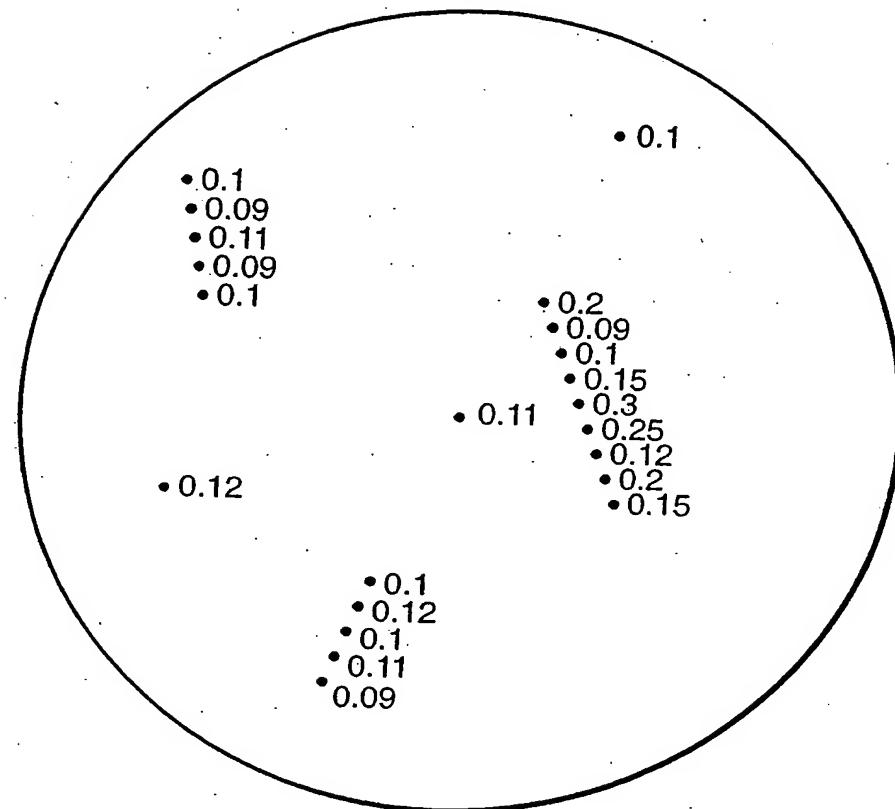


FIG. 4 Simulated Distribution of Defects
After a Scan. Size Indicated in Microns

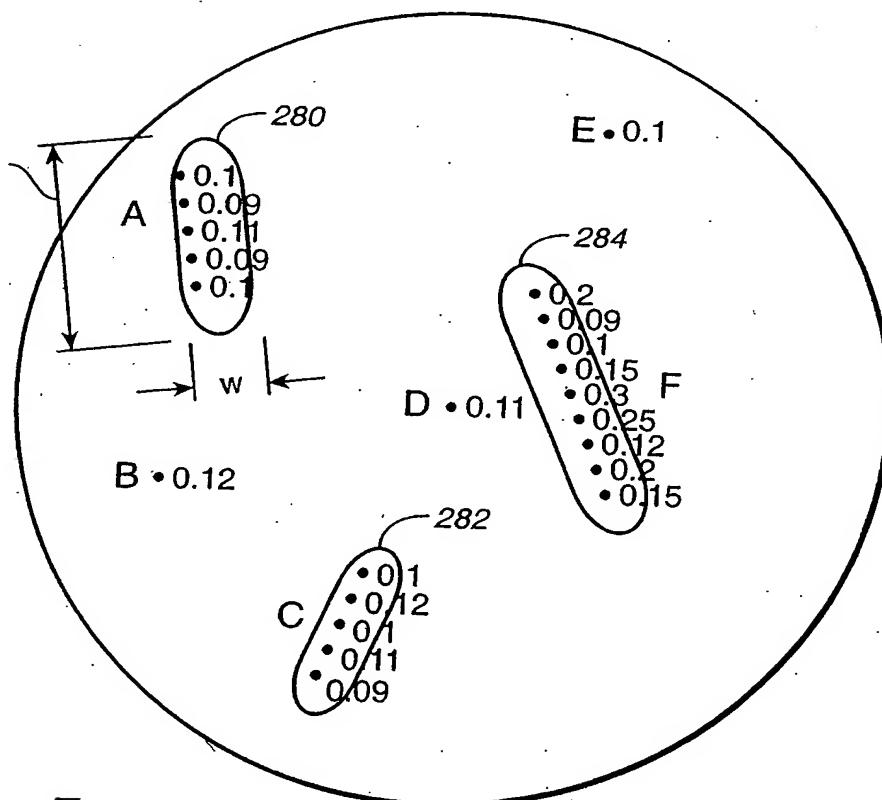
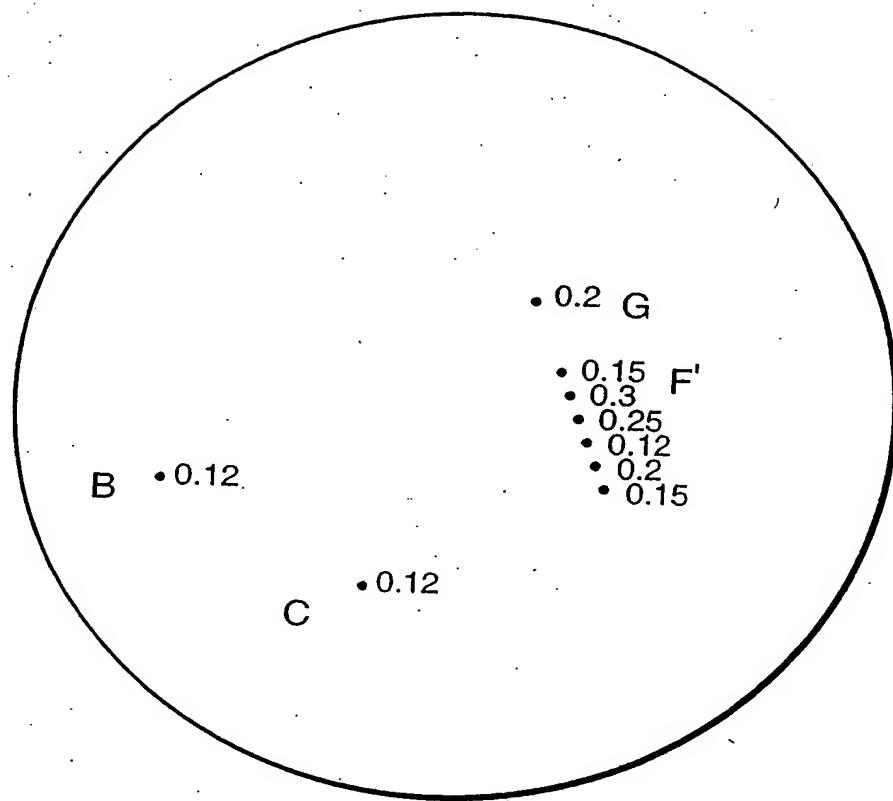


FIG. 5 Initial Clustering in Microscratch Algorithm



Final Output of the Microscratch Algorithm

FIG.-6

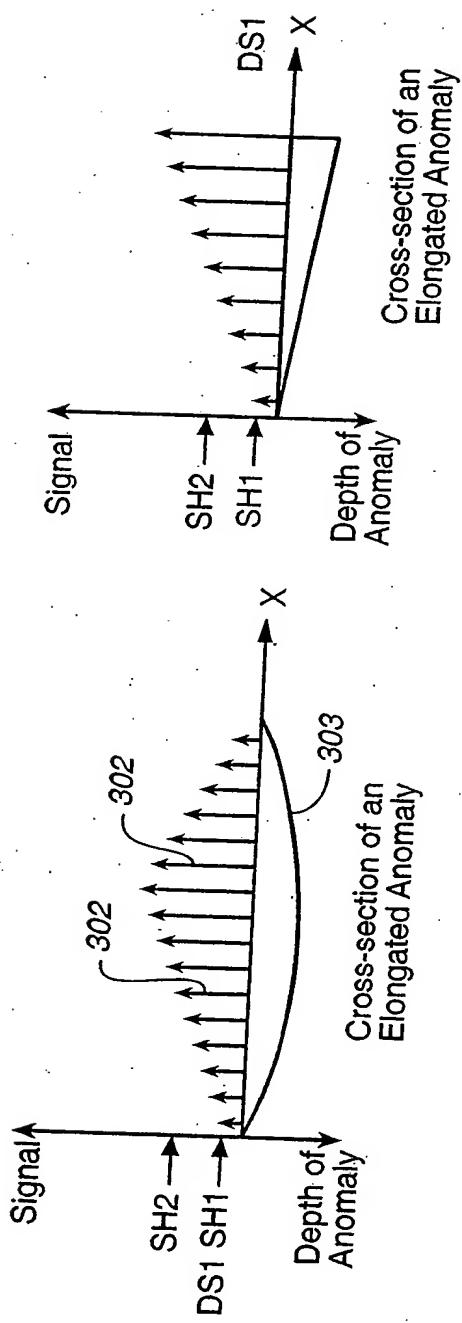


FIG. - 7B

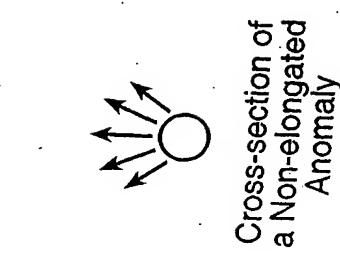


FIG. - 8B

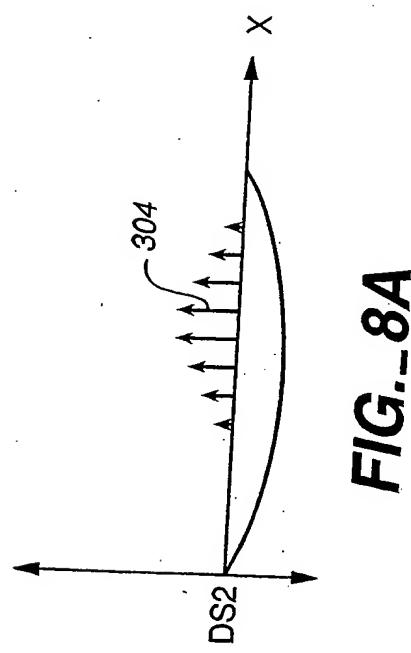


FIG. - 8A

FIG. - 9

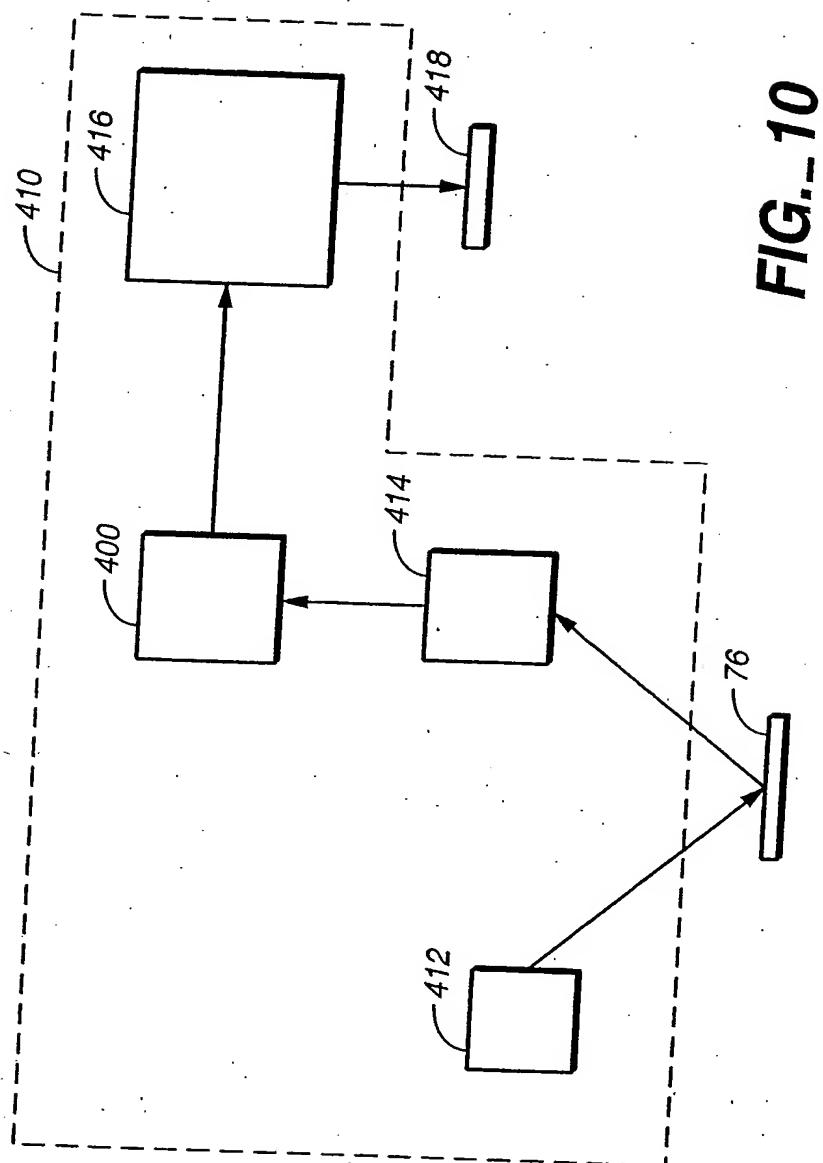


FIG.-10